

Application/Control No.	Applicant(s)/Patent under Reexamination
10/521,594	IWASAKI ET AL.
Examiner	Art Unit
EDMUND H. LEE	1791

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH N (INCLUDING SEAR	IOTES CH STRATEGY)
	DATE	EXMR
264/550,549,294,296,134	10/28/2007	EHL
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inventoir		